Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination		
10/688,429	HEFTY ET AL.		
Examiner	Art Unit		
Feben M. Haile	2616		

SEARCHED				
Class	Subclass	Date	Examiner	
370	231	4/30/2007	FH	
370	236	4/30/2007	· FH	
370	395.71	4/30/2007	FH	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARC	H STRATEGY)
	DATE	EXMR
Search: buffer, queue, storage, memory, credit,	4/30/2007	FH
Updated Search	10/17/2007	FH